Motorola reserves the right to make changes without further notice to any products herein to improve reliability, function or design. Motorola does not assume any liability arising out of the application or use of any product or circuit described herein; neither does it convey any license under its patent rights nor the rights of others. Motorola products are not designed, intended, or authorized for use as components in systems intended for surgical implant into the body, or other applications intended to support or sustain life, or for any other application in which the failure of the Motorola product could create a situation where personal injury or death may occur. Should Buyer purchase or use Motorola products for any such unintended or unauthorized application, Buyer shall indemnify and hold Motorola and its officers, employees, subsidiaries, affiliates, and distributors harmless against all claims, costs, damages, and expenses, and reasonable attorney fees arising out of, directly or indirectly, any claim of personal injury or death associated with such unintended or unauthorized use, even if such claim alleges that Motorola was negligent regarding the design or manufacture of the part.
Revision History

<table>
<thead>
<tr>
<th>Version Number</th>
<th>Revision Date</th>
<th>Effective Date</th>
<th>Author</th>
<th>Description of Changes</th>
</tr>
</thead>
<tbody>
<tr>
<td>00.00</td>
<td>27-10-2000</td>
<td>-</td>
<td>-</td>
<td>Initial SRS2 release.</td>
</tr>
<tr>
<td>01.00</td>
<td>06-06-2001</td>
<td>-</td>
<td>-</td>
<td>Updated the description of ATDDIEN and PORTAD1 register.</td>
</tr>
<tr>
<td>01.10</td>
<td>16-06-2001</td>
<td>-</td>
<td>-</td>
<td>Made SRS2 Compliant</td>
</tr>
<tr>
<td>V02.00</td>
<td>20 June 2001</td>
<td>20 June 2001</td>
<td>-</td>
<td>Reworked whole document to make it more user friendly</td>
</tr>
<tr>
<td>V02.01</td>
<td>26 July 2001</td>
<td>-</td>
<td>-</td>
<td>Added document names Variable definitions and names have been hidden</td>
</tr>
<tr>
<td>V02.02</td>
<td>5 Sept 2001</td>
<td>5 Sept 2001</td>
<td>-</td>
<td>Corrected sampling phase description, other minor corrections</td>
</tr>
<tr>
<td>V02.03</td>
<td>8 Nov 2001</td>
<td>8 Nov 2001</td>
<td>-</td>
<td>Corrected AWAI bit description</td>
</tr>
<tr>
<td>V02.04</td>
<td>16 Jan 2002</td>
<td>16 Jan 2002</td>
<td>-</td>
<td>Syntax corrections</td>
</tr>
<tr>
<td>V02.05</td>
<td>8 Mar 2002</td>
<td>8 Mar 2002</td>
<td>-</td>
<td>Removed document number from all pages except cover sheet</td>
</tr>
<tr>
<td>V02.06</td>
<td>11 Apr 2002</td>
<td>11 Apr 2002</td>
<td>-</td>
<td>Documented special channel conversion in ATDTEST1 register</td>
</tr>
<tr>
<td>V02.07</td>
<td>22 Apr 2002</td>
<td>22 Apr 2002</td>
<td>-</td>
<td>Corrected Table &quot;Available Result Data Formats&quot;</td>
</tr>
<tr>
<td>V02.08</td>
<td>16 Aug 2002</td>
<td>16 Aug 2002</td>
<td>-</td>
<td>FIFOR flag: corrected clearing mechanism B)</td>
</tr>
<tr>
<td>V02.09</td>
<td>23 Aug 2002</td>
<td>23 Aug 2002</td>
<td>-</td>
<td>Detailed AWAI Bit description. Functional Description: Detailed and corrected Low power modes Table &quot;Available Result Data Formats&quot;: Re-corrected</td>
</tr>
<tr>
<td>V02.10</td>
<td>21 Feb 2003</td>
<td>21 Feb 2003</td>
<td>-</td>
<td>Formal corrections on ATDTEST0/1 and ATDDRHx/ATDDRLx register descriptions</td>
</tr>
</tbody>
</table>

Table 0-1 Revision History
Table of Contents

Section 1 Introduction
1.1 Overview .......................................................... 9
1.2 Features .......................................................... 9
1.3 Modes of Operation .............................................. 9
1.3.1 Conversion modes ........................................... 9
1.3.2 MCU Operating Modes ...................................... 9
1.4 Block Diagram .................................................. 10

Section 2 Signal Description
2.1 Overview .......................................................... 11
2.2 Detailed Signal Descriptions .................................. 11
2.2.1 AN7 / ETRIG / PAD7 ......................................... 11
2.2.2 AN6 / PAD6 ..................................................... 11
2.2.3 AN5 / PAD5 ..................................................... 11
2.2.4 AN4 / PAD4 ..................................................... 11
2.2.5 AN3 / PAD3 ..................................................... 11
2.2.6 AN2 / PAD2 ..................................................... 11
2.2.7 AN1 / PAD1 ..................................................... 11
2.2.8 AN0 / PAD0 ..................................................... 11
2.2.9 VRH, VRL ....................................................... 12
2.2.10 VDDA, VSSA ............................................... 12

Section 3 Memory Map and Register Definition
3.1 Overview .......................................................... 13
3.2 Module Memory Map ............................................. 13
3.3 Register Descriptions ........................................... 14
3.3.1 Reserved Register (ATDCTL0) ............................ 14
3.3.2 Reserved Register (ATDCTL1) ............................ 14
3.3.3 ATD Control Register 2 (ATDCTL2) ...................... 14
3.3.4 ATD Control Register 3 (ATDCTL3) ...................... 16
3.3.5 ATD Control Register 4 (ATDCTL4) ...................... 18
3.3.6 ATD Control Register 5 (ATDCTL5) ...................... 20
3.3.7 ATD Status Register 0 (ATDSTAT0) ...................... 22
3.3.8 Reserved Register (ATDTEST0) ................................................................. .23
3.3.9 ATD Test Register 1 (ATDTEST1) ............................................................. .24
3.3.10 ATD Status Register 1 (ATDSTAT1) ......................................................... .24
3.3.11 ATD Input Enable Register (ATDDIEN) ................................................... .25
3.3.12 Port Data Register (PORTAD) ................................................................. .26
3.3.13 ATD Conversion Result Registers (ATDDRHx/ATDDRLx) ....................... .26

Section 4 Functional Description
4.1 General ................................................................. .29
4.2 Analog Sub-block ................................................................. .29
  4.2.1 Sample and Hold Machine ................................................................. .29
  4.2.2 Analog Input Multiplexer ................................................................. .29
  4.2.3 Sample Buffer Amplifier ................................................................. .29
  4.2.4 Analog-to-Digital (A/D) Machine ..................................................... .29
4.3 Digital Sub-block ................................................................. .30
  4.3.1 External Trigger Input (ETRIG) .......................................................... .30
  4.3.2 General Purpose Digital Input Port Operation .................................... .31
  4.3.3 Low Power Modes ................................................................. .31

Section 5 Resets
5.1 General ................................................................. .33

Section 6 Interrupts
6.1 General ................................................................. .35
List of Figures

Figure 1-1  ATD_10B8C Block Diagram ................................................................. 10
Figure 3-1  Reserved Register (ATDCTL0) ................................................................. 14
Figure 3-2  Reserved Register (ATDCTL1) ................................................................. 14
Figure 3-3  ATD Control Register 2 (ATDCTL2) ......................................................... 15
Figure 3-4  ATD Control Register 3 (ATDCTL3) ......................................................... 16
Figure 3-5  ATD Control Register 4 (ATDCTL4) ......................................................... 18
Figure 3-6  ATD Control Register 5 (ATDCTL5) ......................................................... 20
Figure 3-7  ATD Status Register 0 (ATDSTAT0) ......................................................... 22
Figure 3-8  Reserved Register (ATDTEST0) ............................................................... 23
Figure 3-9  ATD Test Register 1 (ATDTEST1) ............................................................ 24
Figure 3-10 ATD Status Register 1 (ATDSTAT1) ......................................................... 25
Figure 3-11 ATD Input Enable Register (ATDDIEN) .................................................... 25
Figure 3-12 Port Data Register (PORTAD) ............................................................... 26
Figure 3-13 Left Justified, ATD Conversion Result Register, High Byte (ATDDRxH) .... 27
Figure 3-14 Left Justified, ATD Conversion Result Register, Low Byte (ATDDRxL) ..... 27
Figure 3-15 Right Justified, ATD Conversion Result Register, High Byte (ATDDRxH) ... 27
Figure 3-16 Right Justified, ATD Conversion Result Register, Low Byte (ATDDRxL) ... 28
List of Tables

Table 0-1 Revision History ................................................................. 2
Table 3-1 Module Memory Map ............................................................ 13
Table 3-2 External Trigger Configurations ........................................... 16
Table 3-3 Conversion Sequence Length Coding ..................................... 17
Table 3-4 ATD Behavior in Freeze Mode (breakpoint) .......................... 17
Table 3-5 Sample Time Select .............................................................. 18
Table 3-6 Clock Prescaler Values ......................................................... 19
Table 3-7 Available Result Data Formats ............................................ 21
Table 3-8 Left Justified, Signed and Unsigned ATD Output Codes ........... 21
Table 3-9 Analog Input Channel Select Coding ..................................... 22
Table 3-10 Special Channel Select Coding .......................................... 24
Table 4-1 External Trigger Control Bits .............................................. 30
Table 6-1 ATD_10B8C Interrupt Vectors ............................................ 35
Section 1 Introduction

1.1 Overview

The ATD_10B8C is an 8-channel, 10-bit, multiplexed input successive approximation analog-to-digital converter. Refer to device electrical specifications for ATD accuracy.

The block is designed to be upwards compatible with the 68HC11 standard 8-bit A/D converter. In addition, there are new operating modes that are unique to the HC12 design.

1.2 Features

- 8/10 Bit Resolution.
- 7 µsec, 10-Bit Single Conversion Time.
- Sample Buffer Amplifier.
- Programmable Sample Time.
- Left/Right Justified, Signed/Unsigned Result Data.
- External Trigger Control.
- Conversion Completion Interrupt Generation.
- Analog Input Multiplexer for 8 Analog Input Channels.
- Analog/Digital Input Pin Multiplexing.
- 1 to 8 Conversion Sequence Lengths.
- Continuous Conversion Mode.
- Multiple Channel Scans.

1.3 Modes of Operation

1.3.1 Conversion modes

There is software programmable selection between performing single or continuous conversion on a single channel or multiple channels.

1.3.2 MCU Operating Modes

- **Stop Mode**
  Entering Stop Mode causes all clocks to halt and thus the system is placed in a minimum power standby mode. This aborts any conversion sequence in progress. During recovery from Stop Mode, there must be a minimum delay for the Stop Recovery Time $t_{SR}$ before initiating a new ATD conversion sequence.
• **Wait Mode**
  Entered Wait Mode the ATD conversion either continues or aborts for low power depending on the logical value of the AWAIT bit.

• **Freeze Mode**
  In Freeze Mode the ATD_10B8C will behave according to the logical values of the FRZ1 and FRZ0 bits. This is useful for debugging and emulation.

### 1.4 Block Diagram

![ATD_10B8C Block Diagram](image-url)

**Figure 1-1** ATD_10B8C Block Diagram
Section 2 Signal Description

2.1 Overview

The ATD_10B8C has a total of 12 external pins.

2.2 Detailed Signal Descriptions

2.2.1 AN7 / ETRIG / PAD7

This pin serves as the analog input Channel 7. It can be configured to provide an external trigger for the ATD conversion. It can be configured as general purpose digital input.

2.2.2 AN6 / PAD6

This pin serves as the analog input Channel 6. It can be configured as general purpose digital input.

2.2.3 AN5 / PAD5

This pin serves as the analog input Channel 5. It can be configured as general purpose digital input.

2.2.4 AN4 / PAD4

This pin serves as the analog input Channel 4. It can be configured as general purpose digital input.

2.2.5 AN3 / PAD3

This pin serves as the analog input Channel 3. It can be configured as general purpose digital input.

2.2.6 AN2 / PAD2

This pin serves as the analog input Channel 2. It can be configured as general purpose digital input.

2.2.7 AN1 / PAD1

This pin serves as the analog input Channel 1. It can be configured as general purpose digital input.

2.2.8 AN0 / PAD0

This pin serves as the analog input Channel 0. It can be configured as general purpose digital input.
2.2.9 VRH, VRL

VRH is the high reference voltage and VRL is the low reference voltage for ATD conversion.

2.2.10 VDDA, VSSA

These pins are the power supplies for the analog circuitry of the ATD_10B8C block.
### Section 3  Memory Map and Register Definition

#### 3.1 Overview

This section provides a detailed description of all registers accessible in the ATD_10B8C.

#### 3.2 Module Memory Map

Table 3-1 gives an overview on all ATD_10B8C registers.

<table>
<thead>
<tr>
<th>Address Offset</th>
<th>Use</th>
<th>Access</th>
</tr>
</thead>
<tbody>
<tr>
<td>$.00</td>
<td>ATD Control Register 0 (ATDCTL0)$^1$</td>
<td>R</td>
</tr>
<tr>
<td>$.01</td>
<td>ATD Control Register 1 (ATDCTL1)$^2$</td>
<td>R</td>
</tr>
<tr>
<td>$.02</td>
<td>ATD Control Register 2 (ATDCTL2)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.03</td>
<td>ATD Control Register 3 (ATDCTL3)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.04</td>
<td>ATD Control Register 4 (ATDCTL4)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.05</td>
<td>ATD Control Register 5 (ATDCTL5)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.06</td>
<td>ATD Status Register 0 (ATDSTAT0)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.07</td>
<td>Unimplemented</td>
<td></td>
</tr>
<tr>
<td>$.08</td>
<td>ATD Test Register 0 (ATDTEST0)$^3$</td>
<td>R</td>
</tr>
<tr>
<td>$.09</td>
<td>ATD Test Register 1 (ATDTEST1)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.0A</td>
<td>Unimplemented</td>
<td></td>
</tr>
<tr>
<td>$.0B</td>
<td>ATD Status Register 1 (ATDSTAT1)</td>
<td>R</td>
</tr>
<tr>
<td>$.0C</td>
<td>Unimplemented</td>
<td></td>
</tr>
<tr>
<td>$.0D</td>
<td>ATD Input Enable Register (ATDDIEN)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.0E</td>
<td>Unimplemented</td>
<td></td>
</tr>
<tr>
<td>$.0F</td>
<td>Port Data Register (PORTAD)</td>
<td>R</td>
</tr>
<tr>
<td>$.10, $.11</td>
<td>ATD Result Register 0 (ATDDR0H, ATDDR0L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.12, $.13</td>
<td>ATD Result Register 1 (ATDDR1H, ATDDR1L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.14, $.15</td>
<td>ATD Result Register 2 (ATDDR2H, ATDDR2L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.16, $.17</td>
<td>ATD Result Register 3 (ATDDR3H, ATDDR3L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.18, $.19</td>
<td>ATD Result Register 4 (ATDDR4H, ATDDR4L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.1A, $.1B</td>
<td>ATD Result Register 5 (ATDDR5H, ATDDR5L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.1C, $.1D</td>
<td>ATD Result Register 6 (ATDDR6H, ATDDR6L)</td>
<td>R/W</td>
</tr>
<tr>
<td>$.1E, $.1F</td>
<td>ATD Result Register 7 (ATDDR7H, ATDDR7L)</td>
<td>R/W</td>
</tr>
</tbody>
</table>

**NOTES:**
1. ATDCTL0 is intended for factory test purposes only.
2. ATDCTL1 is intended for factory test purposes only.
3. ATDTEST0 is intended for factory test purposes only.

**NOTE:**  
Register Address = Base Address + Address Offset, where the Base Address is defined at the MCU level and the Address Offset is defined at the module level.
3.3 Register Descriptions

This section describes in address order all the ATD_10B8C registers and their individual bits.

3.3.1 Reserved Register (ATDCTL0)

![Figure 3-1 Reserved Register (ATDCTL0)](Image)

Read: always read $00 in normal modes
Write: unimplemented in normal modes

NOTE: Writing to this registers when in special modes can alter functionality.

3.3.2 Reserved Register (ATDCTL1)

![Figure 3-2 Reserved Register (ATDCTL1)](Image)

Read: always read $00 in normal modes
Write: unimplemented in normal modes

3.3.3 ATD Control Register 2 (ATDCTL2)

This register controls power down, interrupt and external trigger. Writes to this register will abort current conversion sequence but will not start a new sequence.
Figure 3-3  ATD Control Register 2 (ATDCTL2)

Read: anytime  
Write: anytime

ADPU — ATD Power Down
This bit provides on/off control over the ATD_10B8C block allowing reduced MCU power consumption. Because analog electronic is turned off when powered down, the ATD requires a recovery time period after ADPU bit is enabled.

1 = Normal ATD functionality  
0 = Power down ATD

AFFC — ATD Fast Flag Clear All
1 = Changes all ATD conversion complete flags to a fast clear sequence. Any access to a result register will cause the associate CCF flag to clear automatically.
0 = ATD flag clearing operates normally (read the status register ATDSTAT1 before reading the result register to clear the associate CCF flag).

AWAI — ATD Power Down in Wait Mode
When entering Wait Mode this bit provides on/off control over the ATD_10B8C block allowing reduced MCU power. Because analog electronic is turned off when powered down, the ATD requires a recovery time period after exit from Wait mode.

1 = Halt conversion and power down ATD during Wait mode  
   After exiting Wait mode with an interrupt conversion will resume. But due to the recovery time the result of this conversion should be ignored.  
0 = ATD continues to run in Wait mode

ETRIGLE — External Trigger Level/Edge Control
This bit controls the sensitivity of the external trigger signal. See Table 3-2 for details.

ETRIGP — External Trigger Polarity
This bit controls the polarity of the external trigger signal. See Table 3-2 for details.
**ETRIGE — External Trigger Mode Enable**

This bit enables the external trigger on ATD channel 7. The external trigger allows to synchronize sample and ATD conversions processes with external events.

- 1 = Enable external trigger
- 0 = Disable external trigger

**NOTE:** *The conversion results for the external trigger ATD channel 7 have no meaning while external trigger mode is enabled.*

**ASCIE — ATD Sequence Complete Interrupt Enable**

1 = ATD Interrupt will be requested whenever ASCIF=1 is set.
0 = ATD Sequence Complete interrupt requests are disabled.

**ASCIF — ATD Sequence Complete Interrupt Flag**

If ASCIE=1 the ASCIF flag equals the SCF flag (see 3.3.7), else ASCIF reads zero. Writes have no effect.

- 1 = ATD sequence complete interrupt pending
- 0 = No ATD interrupt occurred

### 3.3.4 ATD Control Register 3 (ATDCTL3)

This register controls the conversion sequence length, FIFO for results registers and behavior in Freeze Mode. Writes to this register will abort current conversion sequence but will not start a new sequence.

<table>
<thead>
<tr>
<th>ETRIGLE</th>
<th>ETRIGP</th>
<th>External Trigger Sensitivity</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>falling edge</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>rising edge</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>low level</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>high level</td>
</tr>
</tbody>
</table>

**Figure 3-4 ATD Control Register 3 (ATDCTL3)**

Read: anytime

Write: anytime
ATD Block User Guide — V02.10

S8C, S4C, S2C, S1C — Conversion Sequence Length

These bits control the number of conversions per sequence. Table 3-3 shows all combinations. At reset, S4C is set to 1 (sequence length is 4). This is to maintain software continuity to HC12 family.

Table 3-3 Conversion Sequence Length Coding

<table>
<thead>
<tr>
<th>S8C</th>
<th>S4C</th>
<th>S2C</th>
<th>S1C</th>
<th>Number of Conversions per Sequence</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>8</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>0</td>
<td>1</td>
<td>1</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>1</td>
<td>0</td>
<td>2</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>1</td>
<td>1</td>
<td>3</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>0</td>
<td>0</td>
<td>4</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>0</td>
<td>1</td>
<td>5</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>1</td>
<td>0</td>
<td>6</td>
</tr>
<tr>
<td>1</td>
<td>X</td>
<td>X</td>
<td>X</td>
<td>8</td>
</tr>
</tbody>
</table>

FIFO — Result Register FIFO Mode

If this bit is zero (non-FIFO mode), the A/D conversion results map into the result registers based on the conversion sequence; the result of the first conversion appears in the first result register, the second result in the second result register, and so on.

If this bit is one (FIFO mode) the conversion counter is not reset at the beginning or end of a conversion sequence; conversion results are placed in consecutive result registers between sequences. The result register counter wraps around when it reaches the end of the result register file. The conversion counter value in ATDSTAT0 can be used to determine where in the result register file, the current conversion result will be placed.

Finally, which result registers hold valid data can be tracked using the conversion complete flags. Fast flag clear mode may or may not be useful in a particular application to track valid data.

FRZ1, FRZ0 — Background Debug Freeze Enable

When debugging an application, it is useful in many cases to have the ATD pause when a breakpoint (Freeze Mode) is encountered. These 2 bits determine how the ATD will respond to a breakpoint as shown in Table 3-4. Leakage onto the storage node and comparator reference capacitors may compromise the accuracy of an immediately frozen conversion depending on the length of the freeze period.

Table 3-4 ATD Behavior in Freeze Mode (breakpoint)

<table>
<thead>
<tr>
<th>FRZ1</th>
<th>FRZ0</th>
<th>Behavior in Freeze mode</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>Continue conversion</td>
</tr>
</tbody>
</table>
3.3.5 ATD Control Register 4 (ATDCTL4)

This register selects the conversion clock frequency, the length of the second phase of the sample time and the resolution of the A/D conversion (i.e.: 8-bits or 10-bits). Writes to this register will abort current conversion sequence but will not start a new sequence.

**Table 3-5 Sample Time Select**

<table>
<thead>
<tr>
<th>SMP1</th>
<th>SMP0</th>
<th>Length of 2nd phase of sample time</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>2 A/D conversion clock periods</td>
</tr>
</tbody>
</table>

Figure 3-5 ATD Control Register 4 (ATDCTL4)

Read: anytime

Write: anytime

SRES8 — A/D Resolution Select

This bit selects the resolution of A/D conversion results as either 8 or 10 bits. The A/D converter has an accuracy of 10 bits; however, if low resolution is required, the conversion can be speeded up by selecting 8-bit resolution.

1 = 8 bit resolution
0 = 10 bit resolution

SMP1, SMP0 — Sample Time Select

These two bits select the length of the second phase of the sample time in units of ATD conversion clock cycles. Note that the ATD conversion clock period is itself a function of the prescaler value (bits PRS4-0). The sample time consists of two phases. The first phase is two ATD conversion clock cycles long and transfers the sample quickly (via the buffer amplifier) onto the A/D machine’s storage node. The second phase attaches the external analog signal directly to the storage node for final charging and high accuracy. Table 3-5 lists the lengths available for the second sample phase.
PRS4, PRS3, PRS2, PRS1, PRS0 — ATD Clock Prescaler

These 5 bits are the binary value prescaler value PRS. The ATD conversion clock frequency is calculated as follows:

$$\text{ATDclock} = \frac{\text{BusClock}}{\text{PRS} + 1} \times 0.5$$

Note that the maximum ATD conversion clock frequency is half the Bus Clock. The default (after reset) prescaler value is 5 which results in a default ATD conversion clock frequency that is Bus Clock divided by 12. Table 3-6 illustrates the divide-by operation and the appropriate range of the Bus Clock.

### Table 3-6 Clock Prescaler Values

<table>
<thead>
<tr>
<th>Prescale Value</th>
<th>Total Divisor Value</th>
<th>Max. Bus Clock&lt;sup&gt;1&lt;/sup&gt;</th>
<th>Min. Bus Clock&lt;sup&gt;2&lt;/sup&gt;</th>
</tr>
</thead>
<tbody>
<tr>
<td>00000</td>
<td>divide by 2</td>
<td>4 MHz</td>
<td>1 MHz</td>
</tr>
<tr>
<td>00001</td>
<td>divide by 4</td>
<td>8 MHz</td>
<td>2 MHz</td>
</tr>
<tr>
<td>00010</td>
<td>divide by 6</td>
<td>12 MHz</td>
<td>3 MHz</td>
</tr>
<tr>
<td>00011</td>
<td>divide by 8</td>
<td>16 MHz</td>
<td>4 MHz</td>
</tr>
<tr>
<td>00100</td>
<td>divide by 10</td>
<td>20 MHz</td>
<td>5 MHz</td>
</tr>
<tr>
<td>00101</td>
<td>divide by 12</td>
<td>24 MHz</td>
<td>6 MHz</td>
</tr>
<tr>
<td>00110</td>
<td>divide by 14</td>
<td>28 MHz</td>
<td>7 MHz</td>
</tr>
<tr>
<td>00111</td>
<td>divide by 16</td>
<td>32 MHz</td>
<td>8 MHz</td>
</tr>
<tr>
<td>01000</td>
<td>divide by 18</td>
<td>36 MHz</td>
<td>9 MHz</td>
</tr>
<tr>
<td>01001</td>
<td>divide by 20</td>
<td>40 MHz</td>
<td>10 MHz</td>
</tr>
<tr>
<td>01010</td>
<td>divide by 22</td>
<td>44 MHz</td>
<td>11 MHz</td>
</tr>
<tr>
<td>01011</td>
<td>divide by 24</td>
<td>48 MHz</td>
<td>12 MHz</td>
</tr>
<tr>
<td>01100</td>
<td>divide by 26</td>
<td>52 MHz</td>
<td>13 MHz</td>
</tr>
<tr>
<td>01101</td>
<td>divide by 28</td>
<td>56 MHz</td>
<td>14 MHz</td>
</tr>
<tr>
<td>01110</td>
<td>divide by 30</td>
<td>60 MHz</td>
<td>15 MHz</td>
</tr>
<tr>
<td>01111</td>
<td>divide by 32</td>
<td>64 MHz</td>
<td>16 MHz</td>
</tr>
<tr>
<td>10000</td>
<td>divide by 34</td>
<td>68 MHz</td>
<td>17 MHz</td>
</tr>
<tr>
<td>10001</td>
<td>divide by 36</td>
<td>72 MHz</td>
<td>18 MHz</td>
</tr>
<tr>
<td>10010</td>
<td>divide by 38</td>
<td>76 MHz</td>
<td>19 MHz</td>
</tr>
<tr>
<td>10011</td>
<td>divide by 40</td>
<td>80 MHz</td>
<td>20 MHz</td>
</tr>
<tr>
<td>10100</td>
<td>divide by 42</td>
<td>84 MHz</td>
<td>21 MHz</td>
</tr>
<tr>
<td>10101</td>
<td>divide by 44</td>
<td>88 MHz</td>
<td>22 MHz</td>
</tr>
<tr>
<td>10110</td>
<td>divide by 46</td>
<td>92 MHz</td>
<td>23 MHz</td>
</tr>
<tr>
<td>10111</td>
<td>divide by 48</td>
<td>96 MHz</td>
<td>24 MHz</td>
</tr>
<tr>
<td>11000</td>
<td>divide by 50</td>
<td>100 MHz</td>
<td>25 MHz</td>
</tr>
<tr>
<td>11001</td>
<td>divide by 52</td>
<td>104 MHz</td>
<td>26 MHz</td>
</tr>
<tr>
<td>11010</td>
<td>divide by 54</td>
<td>108 MHz</td>
<td>27 MHz</td>
</tr>
<tr>
<td>11011</td>
<td>divide by 56</td>
<td>112 MHz</td>
<td>28 MHz</td>
</tr>
<tr>
<td>11100</td>
<td>divide by 58</td>
<td>116 MHz</td>
<td>29 MHz</td>
</tr>
<tr>
<td>11101</td>
<td>divide by 60</td>
<td>120 MHz</td>
<td>30 MHz</td>
</tr>
<tr>
<td>11110</td>
<td>divide by 62</td>
<td>124 MHz</td>
<td>31 MHz</td>
</tr>
<tr>
<td>11111</td>
<td>divide by 64</td>
<td>128 MHz</td>
<td>32 MHz</td>
</tr>
</tbody>
</table>
NOTE:
1. Maximum ATD conversion clock frequency is 2MHz. The maximum allowed Bus Clock frequency is shown in this column.
2. Minimum ATD conversion clock frequency is 500KHz. The minimum allowed Bus Clock frequency is shown in this column.

3.3.6 ATD Control Register 5 (ATDCTL5)

This register selects the type of conversion sequence and the analog input channels sampled. Writes to this register will abort current conversion sequence and start a new conversion sequence.

<table>
<thead>
<tr>
<th> </th>
<th>7</th>
<th>6</th>
<th>5</th>
<th>4</th>
<th>3</th>
<th>2</th>
<th>1</th>
<th>0</th>
</tr>
</thead>
<tbody>
<tr>
<td>R/W</td>
<td>DJM</td>
<td>DSGN</td>
<td>SCAN</td>
<td>MULT</td>
<td>0</td>
<td>CC</td>
<td>CB</td>
<td>CA</td>
</tr>
<tr>
<td>RESET:</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
</tr>
</tbody>
</table>

_DJM_ — Result Register Data Justification
This bit controls justification of conversion data in the result registers. See 3.3.13 ATD Conversion Result Registers (ATDDRHx/ATDDRLx) for details.

- 1 = Right justified data in the result registers
- 0 = Left justified data in the result registers

_DSGN_ — Result Register Data Signed or Unsigned Representation
This bit selects between signed and unsigned conversion data representation in the result registers. Signed data is represented as 2’s complement. Signed data is not available in right justification. See 3.3.13 ATD Conversion Result Registers (ATDDRHx/ATDDRLx) for details.

- 1 = Signed data representation in the result registers
- 0 = Unsigned data representation in the result registers

Table 3-7 summarizes the result data formats available and how they are set up using the control bits.

Table 3-8 illustrates the difference between the signed and unsigned, left justified output codes for an input signal range between 0 and 5.12 Volts.
SCAN — Continuous Conversion Sequence Mode
This bit selects whether conversion sequences are performed continuously or only once.
1 = Continuous conversion sequences (scan mode)
0 = Single conversion sequence

MULT — Multi-Channel Sample Mode
When MULT is 0, the ATD sequence controller samples only from the specified analog input channel for an entire conversion sequence. The analog channel is selected by channel selection code (control bits CC/CB/CA located in ATDCTL5). When MULT is 1, the ATD sequence controller samples across channels. The number of channels sampled is determined by the sequence length value (S8C, S4C, S2C, S1C). The first analog channel examined is determined by channel selection code (CC, CB, CA control bits); subsequent channels sampled in the sequence are determined by incrementing the channel selection code.
1 = Sample across several channels
0 = Sample only one channel

CC, CB, CA — Analog Input Channel Select Code
These bits select the analog input channel(s) whose signals are sampled and converted to digital codes. Table 3-9 lists the coding used to select the various analog input channels. In the case of single channel scans (MULT=0), this selection code specified the channel examined. In the case of

### Table 3-7 Available Result Data Formats

<table>
<thead>
<tr>
<th>SRES8</th>
<th>DJM</th>
<th>DSGN</th>
<th>Result Data Formats</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>0</td>
<td>0</td>
<td>8-bit / left justified / unsigned - bits 8-15</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>1</td>
<td>8-bit / left justified / signed - bits 8-15</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>X</td>
<td>8-bit / right justified / unsigned - bits 0-7</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>0</td>
<td>10-bit / left justified / unsigned - bits 6-15</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>1</td>
<td>10-bit / left justified / signed - bits 6-15</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>X</td>
<td>10-bit / right justified / unsigned - bits 0-9</td>
</tr>
</tbody>
</table>

### Table 3-8 Left Justified, Signed and Unsigned ATD Output Codes.

<table>
<thead>
<tr>
<th>Input Signal</th>
<th>Signed 8-Bit Codes</th>
<th>Unsigned 8-Bit Codes</th>
<th>Signed 10-Bit Codes</th>
<th>Unsigned 10-Bit Codes</th>
</tr>
</thead>
<tbody>
<tr>
<td>Vrl = 0 Volts</td>
<td>Vrh = 5.12 Volts</td>
<td></td>
<td></td>
<td></td>
</tr>
<tr>
<td>5.120 Volts</td>
<td>7F</td>
<td>FF</td>
<td>7FC0</td>
<td>FFC0</td>
</tr>
<tr>
<td>5.100</td>
<td>7F</td>
<td>FF</td>
<td>7F00</td>
<td>FF00</td>
</tr>
<tr>
<td>5.080</td>
<td>7E</td>
<td>FE</td>
<td>7E00</td>
<td>FE00</td>
</tr>
<tr>
<td>2.580</td>
<td>01</td>
<td>81</td>
<td>0100</td>
<td>8100</td>
</tr>
<tr>
<td>2.560</td>
<td>00</td>
<td>80</td>
<td>0000</td>
<td>8000</td>
</tr>
<tr>
<td>2.540</td>
<td>FF</td>
<td>7F</td>
<td>FF00</td>
<td>7F00</td>
</tr>
<tr>
<td>0.020</td>
<td>81</td>
<td>01</td>
<td>8100</td>
<td>0100</td>
</tr>
<tr>
<td>0.000</td>
<td>80</td>
<td>00</td>
<td>8000</td>
<td>0000</td>
</tr>
</tbody>
</table>
multi-channel scans (MULT=1), this selection code represents the first channel to be examined in the conversion sequence. Subsequent channels are determined by incrementing channel selection code; selection codes that reach the maximum value wrap around to the minimum value.

### 3.3.7 ATD Status Register 0 (ATDSTAT0)

This read-only register contains the Sequence Complete Flag, overrun flags for external trigger and FIFO mode, and the conversion counter.

#### Table 3-9 Analog Input Channel Select Coding

<table>
<thead>
<tr>
<th>CC</th>
<th>CB</th>
<th>CA</th>
<th>Analog Input Channel</th>
</tr>
</thead>
<tbody>
<tr>
<td>0</td>
<td>0</td>
<td>0</td>
<td>AN0</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>1</td>
<td>AN1</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>0</td>
<td>AN2</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>1</td>
<td>AN3</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>0</td>
<td>AN4</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>1</td>
<td>AN5</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>0</td>
<td>AN6</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>1</td>
<td>AN7</td>
</tr>
</tbody>
</table>

#### Figure 3-7 ATD Status Register 0 (ATDSTAT0)

Read: anytime

Write: anytime (No effect on (CC2, CC1, CC0))

SCF — Sequence Complete Flag

This flag is set upon completion of a conversion sequence. If conversion sequences are continuously performed (SCAN=1), the flag is set after each one is completed. This flag is cleared when one of the following occurs:
A) Write “1” to SCF
B) Write to ATDCTL5 (a new conversion sequence is started)
C) If AFFC=1 and read of a result register
   1 = Conversion sequence has completed
0 = Conversion sequence not completed

**ETORF — External Trigger Overrun Flag**

While in edge trigger mode (ETRIGLE=0), if additional active edges are detected while a conversion sequence is in process the overrun flag is set. This flag is cleared when one of the following occurs:

A) Write “1” to ETORF
B) Write to ATDCTL2, ATDCTL3 or ATDCTL4 (a conversion sequence is aborted)
C) Write to ATDCTL5 (a new conversion sequence is started)

1 = External trigger over run error has occurred
0 = No External trigger over run error has occurred

**FIFOR - FIFO Over Run Flag.**

This bit indicates that a result register has been written to before its associated conversion complete flag (CCF) has been cleared. This flag is most useful when using the FIFO mode because the flag potentially indicates that result registers are out of sync with the input channels. However, it is also practical for non-FIFO modes, and indicates that a result register has been over written before it has been read (i.e. the old data has been lost). This flag is cleared when one of the following occurs:

A) Write “1” to FIFOR
B) Start a new conversion sequence (write to ATDCTL5 or external trigger)

1 = An over run condition exists
0 = No over run has occurred

**CC2, CC1, CC0 — Conversion Counter**

These 3 read-only bits are the binary value of the conversion counter. The conversion counter points to the result register that will receive the result of the current conversion. E.g. CC2=1, CC1=1, CC0=0 indicates that the result of the current conversion will be in ATD Result Register 6. If in non-FIFO mode (FIFO=0) the conversion counter is initialized to zero at the begin and end of the conversion sequence. If in FIFO mode (FIFO=1) the register counter is not initialized. The conversion counters wraps around when its maximum value is reached.

### 3.3.8 Reserved Register (ATDTEST0)

<table>
<thead>
<tr>
<th>7</th>
<th>6</th>
<th>5</th>
<th>4</th>
<th>3</th>
<th>2</th>
<th>1</th>
<th>0</th>
</tr>
</thead>
<tbody>
<tr>
<td>U</td>
<td>U</td>
<td>U</td>
<td>U</td>
<td>U</td>
<td>U</td>
<td>U</td>
<td>U</td>
</tr>
</tbody>
</table>

**RESET:**

<table>
<thead>
<tr>
<th>7</th>
<th>6</th>
<th>5</th>
<th>4</th>
<th>3</th>
<th>2</th>
<th>1</th>
<th>0</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
<td>0</td>
</tr>
</tbody>
</table>

= Unimplemented or Reserved

**Figure 3-8 Reserved Register (ATDTEST0)**

Read: anytime, returns unpredictable values

Write: anytime in special modes, unimplemented in normal modes
NOTE: Writing to this registers when in special modes can alter functionality.

### 3.3.9 ATD Test Register 1 (ATDTEST1)

This register contains the SC bit used to enable special channel conversions.

![Figure 3-9 ATD Test Register 1 (ATDTEST1)]

Read: anytime, returns unpredictable values for Bit7 and Bit6  
Write: anytime  

SC - Special Channel Conversion Bit  

If this bit is set, then special channel conversion can be selected using CC, CB and CA of ATDCTL5.  
**Table 3-10** lists the coding.  

<table>
<thead>
<tr>
<th>SC</th>
<th>CC</th>
<th>CB</th>
<th>CA</th>
<th>Analog Input Channel</th>
</tr>
</thead>
<tbody>
<tr>
<td>1</td>
<td>0</td>
<td>X</td>
<td>X</td>
<td>Reserved</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>0</td>
<td>0</td>
<td>$V_{RH}$</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>0</td>
<td>1</td>
<td>$V_{RL}$</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>1</td>
<td>0</td>
<td>($V_{RH}+V_{RL})/2$</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>1</td>
<td>1</td>
<td>Reserved</td>
</tr>
</tbody>
</table>

**NOTE:** Always write remaining bits of ATDTEST1 (Bit7 to Bit1) zero when writing SC bit. Not doing so might result in unpredictable ATD behavior.

### 3.3.10 ATD Status Register 1 (ATDSTAT1)

This read-only register contains the Conversion Complete Flags.
Figure 3-10  ATD Status Register 1 (ATDSTAT1)

Read: anytime
Write: anytime, no effect

CCFx — Conversion Complete Flag x (x=7,6,5,4,3,2,1,0)

A conversion complete flag is set at the end of each conversion in a conversion sequence. The flags are associated with the conversion position in a sequence (and also the result register number). Therefore, CCF0 is set when the first conversion in a sequence is complete and the result is available in result register ATDDR0; CCF1 is set when the second conversion in a sequence is complete and the result is available in ATDDR1, and so forth. A flag CCFx (x=7,6,5,4,3,2,1,0) is cleared when one of the following occurs:
A) Write to ATDCTL5 (a new conversion sequence is started)
B) If AFFC=0 and read of ATDSTAT1 followed by read of result register ATDDRx
C) If AFFC=1 and read of result register ATDDRx

1 = Conversion number x has completed, result ready in ATDDRx
0 = Conversion number x not completed

3.3.11 ATD Input Enable Register (ATDDIEN)

Figure 3-11  ATD Input Enable Register (ATDDIEN)

Read: anytime
Write: anytime

IENx — ATD Digital Input Enable on channel x (x= 7, 6, 5, 4, 3, 2, 1, 0)

This bit controls the digital input buffer from the analog input pin (ANx) to PTADx data register.

1 = Enable digital input buffer to PTADx.
0 = Disable digital input buffer to PTADx

**NOTE:** Setting this bit will enable the corresponding digital input buffer continuously. If this bit is set while simultaneously using it as an analog port, there is potentially increased power consumption because the digital input buffer maybe in the linear region.

### 3.3.12 Port Data Register (PORTAD)

The data port associated with the ATD is input-only. The port pins are shared with the analog A/D inputs AN7-0.

#### $0F$

<table>
<thead>
<tr>
<th>R</th>
<th>PTAD7</th>
<th>PTAD6</th>
<th>PTAD5</th>
<th>PTAD4</th>
<th>PTAD3</th>
<th>PTAD2</th>
<th>PTAD1</th>
<th>PTAD0</th>
</tr>
</thead>
<tbody>
<tr>
<td>W</td>
<td>RESET:</td>
<td>1</td>
<td>1</td>
<td>1</td>
<td>1</td>
<td>1</td>
<td>1</td>
<td>1</td>
</tr>
</tbody>
</table>

**Figure 3-12 Port Data Register (PORTAD)**

Read: anytime  
Write: anytime, no effect  

The A/D input channels may be used for general purpose digital input.

PTADx — A/D Channel x (ANx) Digital Input (x= 7,6,5,4,3,2,1,0)

If the digital input buffer on the ANx pin is enabled (IENx=1) read returns the logic level on ANx pin (signal potentials not meeting VIL or VIH specifications will have an indeterminate value)).

If the digital input buffers are disabled (IENx=0), read returns a “1”.

Reset sets all PORTAD bits to “1”.

### 3.3.13 ATD Conversion Result Registers (ATDDRHx/ATDDRLx)

The A/D conversion results are stored in 8 read-only result registers ATDDRHx/ATDDRLx. The result data is formatted in the result registers based on two criteria. First there is left and right justification; this selection is made using the DJM control bit in ATDCTL5. Second there is signed and unsigned data; this selection is made using the DSGN control bit in ATDCTL5. Signed data is stored in 2’s complement format and only exists in left justified format. Signed data selected for right justified format is ignored.

Read: anytime  
Write: anytime, no effect in normal modes
3.3.13.1 Left Justified Result Data

\$_10 = ATDDR0H, \$_12 = ATDDR1H, \$_14 = ATDDR2H, \$_16 = ATDDR3H
\$_18 = ATDDR4H, \$_1A = ATDDR5H, \$_1C = ATDDR6H, \$_1E = ATDDR7H

3.3.13.2 Right Justified Result Data

\$_10 = ATDDR0H, \$_12 = ATDDR1H, \$_14 = ATDDR2H, \$_16 = ATDDR3H
\$_18 = ATDDR4H, \$_1A = ATDDR5H, \$_1C = ATDDR6H, \$_1E = ATDDR7H
Figure 3-16 Right Justified, ATD Conversion Result Register, Low Byte (ATDDRxL)

<table>
<thead>
<tr>
<th>R</th>
<th>W</th>
</tr>
</thead>
<tbody>
<tr>
<td>7</td>
<td>BIT 7 MSB</td>
</tr>
<tr>
<td>6</td>
<td>BIT 6</td>
</tr>
<tr>
<td>5</td>
<td>BIT 5</td>
</tr>
<tr>
<td>4</td>
<td>BIT 4</td>
</tr>
<tr>
<td>3</td>
<td>BIT 3</td>
</tr>
<tr>
<td>2</td>
<td>BIT 2</td>
</tr>
<tr>
<td>1</td>
<td>BIT 1</td>
</tr>
<tr>
<td>0</td>
<td>BIT 0</td>
</tr>
</tbody>
</table>

RESET: 0 0 0 0 0 0 0 0 0 0 10-bit data

8-bit data

\[ \_11 = \text{ATDDR0L}, \_13 = \text{ATDDR1L}, \_15 = \text{ATDDR2L}, \_17 = \text{ATDDR3L} \]
\[ \_19 = \text{ATDDR4L}, \_1B = \text{ATDDR5L}, \_1D = \text{ATDDR6L}, \_1F = \text{ATDDR7L} \]

\( = \text{Unimplemented or Reserved} \)
Section 4 Functional Description

4.1 General

The ATD_10B8C is structured in an analog and a digital sub-block.

4.2 Analog Sub-block

The analog sub-block contains all analog electronics required to perform a single conversion. Separate power supplies VDDA and VSSA allow to isolate noise of other MCU circuitry from the analog sub-block.

4.2.1 Sample and Hold Machine

The Sample and Hold (S/H) Machine accepts analog signals from the external surroundings and stores them as capacitor charge on a storage node.

The sample process uses a two stage approach. During the first stage, the sample amplifier is used to quickly charge the storage node. The second stage connects the input directly to the storage node to complete the sample for high accuracy.

When not sampling, the sample and hold machine disables its own clocks. The analog electronics still draw their quiescent current. The power down (ADPU) bit must be set to disable both the digital clocks and the analog power consumption.

The input analog signals are unipolar and must fall within the potential range of VSSA to VDDA.

4.2.2 Analog Input Multiplexer

The analog input multiplexer connects one of the 8 external analog input channels to the sample and hold machine.

4.2.3 Sample Buffer Amplifier

The sample amplifier is used to buffer the input analog signal so that the storage node can be quickly charged to the sample potential.

4.2.4 Analog-to-Digital (A/D) Machine

The A/D Machine performs analog to digital conversions. The resolution is program selectable at either 8 or 10 bits. The A/D machine uses a successive approximation architecture. It functions by comparing the stored analog sample potential with a series of digitally generated analog potentials. By following a binary search algorithm, the A/D machine locates the approximating potential that is nearest to the sampled potential.
When not converting the A/D machine disables its own clocks. The analog electronics still draws quiescent current. The power down (ADPU) bit must be set to disable both the digital clocks and the analog power consumption.

Only analog input signals within the potential range of $V_{RL}$ to $V_{RH}$ (A/D reference potentials) will result in a non-railed digital output codes.

### 4.3 Digital Sub-block

This subsection explains some of the digital features in more detail. See register descriptions for all details.

#### 4.3.1 External Trigger Input (ETRIG)

The external trigger feature allows the user to synchronize ATD conversions to the external environment events rather than relying on software to signal the ATD module when ATD conversions are to take place. The input signal (ATD channel 7) is programmable to be edge or level sensitive with polarity control. Table 4-1 gives a brief description of the different combinations of control bits and their affect on the external trigger function.

<table>
<thead>
<tr>
<th>ETRIGLE</th>
<th>ETRIGP</th>
<th>ETRIGE</th>
<th>SCAN</th>
<th>Description</th>
</tr>
</thead>
<tbody>
<tr>
<td>X</td>
<td>X</td>
<td>0</td>
<td>0</td>
<td>Ignores external trigger. Performs one conversion sequence and stops.</td>
</tr>
<tr>
<td>X</td>
<td>X</td>
<td>0</td>
<td>1</td>
<td>Ignores external trigger. Performs continuous conversion sequences.</td>
</tr>
<tr>
<td>0</td>
<td>0</td>
<td>1</td>
<td>X</td>
<td>Falling edge triggered. Performs one conversion sequence per trigger.</td>
</tr>
<tr>
<td>0</td>
<td>1</td>
<td>1</td>
<td>X</td>
<td>Rising edge triggered. Performs one conversion sequence per trigger.</td>
</tr>
<tr>
<td>1</td>
<td>0</td>
<td>1</td>
<td>X</td>
<td>Trigger active low. Performs continuous conversions while trigger is active.</td>
</tr>
<tr>
<td>1</td>
<td>1</td>
<td>1</td>
<td>X</td>
<td>Trigger active high. Performs continuous conversions while trigger is active.</td>
</tr>
</tbody>
</table>

During a conversion, if additional active edges are detected the overrun error flag ETORF is set.

In either level or edge triggered modes, the first conversion begins when the trigger is received. In both cases, the maximum latency time is one Bus Clock cycle plus any skew or delay introduced by the trigger circuitry.

**NOTE:** The conversion results for the external trigger ATD channel 7 have no meaning while external trigger mode is enabled.
Once ETRIGE is enabled, conversions cannot be started by a write to ATDCTL5, but rather must be triggered externally.

If the level mode is active and the external trigger both de-asserts and re-asserts itself during a conversion sequence, this does not constitute an overrun; therefore, the flag is not set. If the trigger is left asserted in level mode while a sequence is completing, another sequence will be triggered immediately.

### 4.3.2 General Purpose Digital Input Port Operation

The input channel pins can be multiplexed between analog and digital data. As analog inputs, they are multiplexed and sampled to supply signals to the A/D converter. As digital inputs, they supply external input data that can be accessed through the digital port register PORTAD (input-only).

The analog/digital multiplex operation is performed in the input pads. The input pad is always connected to the analog inputs of the ATD_10B8C. The input pad signal is buffered to the digital port registers. This buffer can be turned on or off with the ATDDIEN register. This is important so that the buffer does not draw excess current when analog potentials are presented at its input.

### 4.3.3 Low Power Modes

The ATD_10B8C can be configured for lower MCU power consumption in 3 different ways:

- **Stop Mode**: This halts A/D conversion. Exit from Stop mode will resume A/D conversion, but due to the recovery time the result of this conversion should be ignored.
- **Wait Mode with AWAI=1**: This halts A/D conversion. Exit from Wait mode will resume A/D conversion, but due to the recovery time the result of this conversion should be ignored.
- **Writing ADPU=0** (Note that all ATD registers remain accessible.): This aborts any A/D conversion in progress.

Note that the reset value for the ADPU bit is zero. Therefore, when this module is reset, it is reset into the power down state.
Section 5  Resets

5.1 General

At reset the ATD_10B8C is in a power down state. The reset state of each individual bit is listed within the Register Description section (see Section 3 Memory Map and Register Definition) which details the registers and their bit-field.
Section 6 Interrupts

6.1 General

The interrupt requested by the ATD_10B8C is listed in Table 6-1. Refer to MCU specification for related vector address and priority.

<table>
<thead>
<tr>
<th>Interrupt Source</th>
<th>CCR Mask</th>
<th>Local Enable</th>
</tr>
</thead>
<tbody>
<tr>
<td>Sequence Complete Interrupt</td>
<td>I bit</td>
<td>ASCIE in ATDCTL2</td>
</tr>
</tbody>
</table>

See register descriptions for further details.